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---

1 **Mated-film memory production--A progress report**
Overn, W.; Root, M.;
Magnetics, IEEE Transactions on , Volume: 8 , Issue: 3 , Sep 1972
Pages:361 - 361

[Abstract] [PDF Full-Text (136 KB)] **IEEE JNL**

---

2 **A 32-Bit Custom VLSI Processor for Communications Network Nodes**
Niwa, A.; Yamada, T.;
Selected Areas in Communications, IEEE Journal on , Volume: 4 , Issue: 1 , Jan 1986
Pages:192 - 199

[Abstract] [PDF Full-Text (880 KB)] **IEEE JNL**

---

3 **Characterization of operational time variability using effective process times**
Jacobs, J.H.; Etman, L.F.P.; van Campen, E.J.J.; Rooda, J.E.;
Semiconductor Manufacturing, IEEE Transactions on , Volume: 16 , Issue: 3 , Aug. 2003
Pages:511 - 520

[Abstract] [PDF Full-Text (511 KB)] **IEEE JNL**

---

4 **A fuzzy controller for an aeroload simulator using phase plane method**
Sang Yeal Lee; Hyung Suck Cho;
Control Systems Technology, IEEE Transactions on , Volume: 9 , Issue: 6 , Nov. 2001
Pages:791 - 801

[Abstract] [PDF Full-Text (304 KB)] **IEEE JNL**

---

5 **Rocket-triggered lightning studies for the protection of critical assets**
Morris, M.E.; Fisher, R.J.; Schnetzer, G.H.; Merewether, K.O.; Jorgenson, R.E.;
Industry Applications, IEEE Transactions on , Volume: 30 , Issue: 3 , May-June 1994
Pages:791 - 804

[Abstract] [PDF Full-Text (1284 KB)] **IEEE JNL**

---

6 **Effectiveness of zinc oxide surge arresters on substation equipment probabilities of flashover**
Lambert, S.R.;
Power Delivery, IEEE Transactions on , Volume: 3 , Issue: 4 , Oct. 1988
Pages:1928 - 1934

[Abstract] [PDF Full-Text (516 KB)] **IEEE JNL**

---

7 **A holistic approach to overall equipment effectiveness (OEE)**
Loughlin, S.;
Computing & Control Engineering Journal , Volume: 14 , Issue: 6 , Dec. 2003-Jan. 2004
Pages:37 - 42

[Abstract] [PDF Full-Text (538 KB)] IEE JNL

---

8 **Overall equipment effectiveness**
Godfrey, P.;
Manufacturing Engineer , Volume: 81 , Issue: 3 , June 2002
Pages:109 - 112

[Abstract] [PDF Full-Text (623 KB)] IEE JNL

---

9 **Introducing TPM [total productive maintenance]**
Hutchins, D.;
Manufacturing Engineer , Volume: 77 , Issue: 1 , Feb. 1998
Pages:34 - 39

[Abstract] [PDF Full-Text (688 KB)] IEE JNL

---

10 **The SADLI project safety critical software research in the medical diagnostic domain**
Chudleigh, M.; Berridge, C.; May, R.; Butler, J.; Poole, I.;
Computing & Control Engineering Journal , Volume: 6 , Issue: 5 , Oct. 1995
Pages:211 - 215

[Abstract] [PDF Full-Text (464 KB)] IEE JNL

---

11 **Baseline study of noncommercial computer reuse in the United States**
Lynch, J.;
Electronics and the Environment, 2004. Conference Record. 2004 IEEE International Symposium on , 10-13 May 2004
Pages:189 - 194

[Abstract] [PDF Full-Text (1378 KB)] IEEE CNF

---

12 **Tactical oceanography in mine countermeasures**
Tubridy, L.;
Oceans '02 MTS/IEEE , Volume: 3 , 29-31 Oct. 2002
Pages:1400 - 1406 vol.3

[Abstract] [PDF Full-Text (539 KB)] IEEE CNF

---

13 **Using overall equipment effectiveness (OEE) and the equipment improvement process (ET) to improve Fab throughput**
Freck, R.W.;
Advanced Semiconductor Manufacturing Conference and Workshop, 2000
IEEE/SEMI , 12-14 Sept. 2000
Pages:469 - 471

[Abstract] [PDF Full-Text (332 KB)] **IEEE CNF**

---

14 **Manufacturing science in ion implantation**
Glawischnig, H.;
Ion Implantation Technology, 2000. Conference on , 17-22 Sept. 2000
Pages:354 - 359

[Abstract] [PDF Full-Text (424 KB)] **IEEE CNF**

---

15 **A HW/SW co-design environment for multi-media equipments development using inverse problem**
Suzuki, F.; Koizumi, H.; Hiramine, M.; Yamamoto, K.; Yasuura, H.; Okino, K.;
Hardware/Software Codesign, 1997. (CODES/CASHE '97), Proceedings of the Fifth International Workshop on , 24-26 March 1997
Pages:153 - 157

[Abstract] [PDF Full-Text (464 KB)] **IEEE CNF**

---

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---

16 **A systems approach to gate CD control: metrology, throughput, and OEE**
Monahan, K.M.; MacNaughton, C.; Waiman Ng; Quattrini, R.;
Semiconductor Manufacturing Conference Proceedings, 1997 IEEE International Symposium on , 6-8 Oct. 1997
Pages:B53 - B57

[Abstract] [PDF Full-Text (420 KB)] **IEEE CNF**

---

17 **Managing overall equipment effectiveness [OEE] to optimize factory performance**
Pomorski, T.;
Semiconductor Manufacturing Conference Proceedings, 1997 IEEE International Symposium on , 6-8 Oct. 1997
Pages:A33 - A36

[Abstract] [PDF Full-Text (408 KB)] **IEEE CNF**

18 **Measuring manufacturing performance: dimensions and OEE**
Jonsson, P.; Lesshammar, M.;
Innovation in Technology Management - The Key to Global Leadership. PICMET '97: Portland International Conference on Management and Technology , 27-31 July 1997
Pages:799

[Abstract] [PDF Full-Text (60 KB)] **IEEE CNF**

---

19 **Implementation of overall equipment effectiveness (OEE) system at a semiconductor manufacturer**
Giegling, S.; Verdini, W.A.; Haymon, T.; Konopka, J.;
Electronics Manufacturing Technology Symposium, 1997., Twenty-First IEEE/CPMT International , 13-15 Oct. 1997
Pages:93 - 98

[Abstract] [PDF Full-Text (516 KB)] **IEEE CNF**

---

20 **300 mm fab automation technology options and selection criteria**
Weiss, M.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1997. IEEE /SEMI , 10-12 Sept. 1997
Pages:373 - 379

[Abstract] [PDF Full-Text (528 KB)] **IEEE CNF**

---

21 **Staffing analysis tool for operator-machine-lot interference in semiconductor manufacturing**
Meyersdorf, D.; Biron, O.; Ozelkan, E.C.; Fowler, J.W.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1997. IEEE /SEMI , 10-12 Sept. 1997
Pages:335 - 340

[Abstract] [PDF Full-Text (508 KB)] **IEEE CNF**

---

22 **Overall equipment effectiveness (OEE) and cost measurement [semiconductor manufacturing]**
Konopka, J.; Trybula, W.;

Electronics Manufacturing Technology Symposium, 1996., Nineteenth IEEE/CPMT , 14-16 Oct. 1996
Pages:137 - 140

[Abstract] [PDF Full-Text (284 KB)] IEEE CNF

---

23 **Overall equipment effectiveness in resist processing equipment**
Steege, P.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1996. ASMC 96 Proceedings. IEEE/SEMI 1996 , 12-14 Nov. 1996
Pages:76 - 79

[Abstract] [PDF Full-Text (400 KB)] IEEE CNF

---

24 **300 mm tool automation and its impact on fab design and OEE**
Weiss, M.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1996. ASMC 96 Proceedings. IEEE/SEMI 1996 , 12-14 Nov. 1996
Pages:156 - 161

[Abstract] [PDF Full-Text (508 KB)] IEEE CNF

---

25 **User group implementation with a U.S. supplier**
Hossain-Pas, S.; Brennan, J.; Matsuhiro, D.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1996. ASMC 96 Proceedings. IEEE/SEMI 1996 , 12-14 Nov. 1996
Pages:460 - 464

[Abstract] [PDF Full-Text (292 KB)] IEEE CNF

---

26 **Automated experimental design for automatic test equipment software**
Allred, L.G.; Kelly, P.B.; Harames, J.P.;
AUTOTESTCON '96, 'Test Technology and Commercialization'. Conference Record , 16-19 Sept. 1996
Pages:156 - 159

[Abstract] [PDF Full-Text (328 KB)] IEEE CNF

---

27 **The Use of Semi-Submerged Ships to Support New Technology at Sea**

Lang, T.; Bishop, C.; Sturgeon, W.;
OCEANS , Volume: 11 , Sep 1979
Pages:159 - 166

[Abstract] [PDF Full-Text (736 KB)] **IEEE CNF**

---

28 **An effective methodology for improving equipment reliability and reducing excursions during a factory ramp**
Lantz, S.;
Advanced Semiconductor Manufacturing Conference and Workshop, 2003
IEEEI/SEMI , 31 March-1 April 2003
Pages:297 - 302

[Abstract] [PDF Full-Text (445 KB)] **IEEE CNF**

---

29 **Uses and misuses of the 'overall equipment effectiveness' for production management**
da Costa, S.E.G.; de Lima, E.P.;
Engineering Management Conference, 2002. IEMC '02. 2002 IEEE International , Volume: 2 , 18-20 Aug. 2002
Pages:816 - 820 vol.2

[Abstract] [PDF Full-Text (368 KB)] **IEEE CNF**

---

30 **Evaluating ATE features in terms of test escape rates and other cost of test culprits**
Gatej, J.; Lee Song; Pyron, C.; Raina, R.;
Test Conference, 2002. Proceedings. International , 7-10 Oct. 2002
Pages:1040 - 1049

[Abstract] [PDF Full-Text (693 KB)] **IEEE CNF**

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---

31 **Development and deployment of a multi-component Advanced Process Control system for an epitaxy tool**
Moyne, J.; Solakhian, V.; Yershov, A.; Anderson, M.; Mockler-Hebert, D.;
Advanced Semiconductor Manufacturing 2002 IEEE/SEMI Conference and Workshop , 30 April-2 May 2002
Pages:125 - 130

[Abstract] [PDF Full-Text (886 KB)] **IEEE CNF**

---

32 **Preventive logistics system**
Schmidt, S.;
Management of Engineering and Technology, 1999. Technology and Innovation Management. PICMET '99. Portland International Conference on , Volume: 1 , 25-29 July 1999
Pages:326 vol.1

[Abstract] [PDF Full-Text (40 KB)] IEEE CNF

---

33 **Towards a standardized procedure for automatic test equipment timing accuracy evaluation**
Cai, Y.; Ortner, W.R.; Garrenton, C.T.;
Test Conference, 1999. Proceedings. International , 28-30 Sept. 1999
Pages:509 - 517

[Abstract] [PDF Full-Text (916 KB)] IEEE CNF

---

34 **Semiconductor metrics: conflicting goals or increasing opportunities?**
Sattler, L.; Schlueter, R.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1998. 1998 IEEE/SEMI , 23-25 Sept. 1998
Pages:55 - 60

[Abstract] [PDF Full-Text (480 KB)] IEEE CNF

---

35 **Improvement of AME 8110 oxide etcher daily clean**
Welp, K.; Fisher, P.; Holden, J.; Wang, P.; Gunn, M.; Franco, J.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1998. 1998 IEEE/SEMI , 23-25 Sept. 1998
Pages:50 - 54

[Abstract] [PDF Full-Text (308 KB)] IEEE CNF

---

36 **Performance and productivity improvements in an advanced dielectric etch reactor for sub 0.3 µm applications**
Srinivasan, M.; Caple, R.; Hills, G.; Mueller, G.; Nguyen, T.; Wagganer, E.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1998. 1998 IEEE/SEMI , 23-25 Sept. 1998
Pages:419 - 422

[Abstract] [PDF Full-Text (372 KB)] IEEE CNF

---

37 **Utilising a LonWorks control network for factory communication to improve overall equipment effectiveness**
Ziemerink, R.A.; Bodenstein, C.P.;
Industrial Electronics, 1998. Proceedings. ISIE '98. IEEE International Symposium

on , Volume: 2 , 7-10 July 1998
Pages:684 - 689 vol.2

[Abstract] [PDF Full-Text (620 KB)] IEEE CNF

---

38 **Capital productivity-challenge and opportunity**
Rowe, W.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1995. ASMC 95 Proceedings. IEEE/SEMI 1995 , 13-15 Nov. 1995
Pages:23

[Abstract] [PDF Full-Text (36 KB)] IEEE CNF

---

39 **System test cost modelling based on event rate analysis**
Farren, D.; Ambler, A.P.;
Test Conference, 1994. Proceedings., International , 2-6 Oct. 1994
Pages:84 - 92

[Abstract] [PDF Full-Text (780 KB)] IEEE CNF

---

40 **Illuminating systems and equipment selection for industrial control rooms**
Kao Chen; Elam, R.T.;
Industry Applications Society Annual Meeting, 1994., Conference Record of the 1994 IEEE , 2-6 Oct. 1994
Pages:1984 - 1987 vol.3

[Abstract] [PDF Full-Text (388 KB)] IEEE CNF

---

41 **Efficient use of SATCOM resources in MSE networks (DAMA for MSE)**
Biagini, W.; Masciari, M.;
Military Communications Conference, 1993. MILCOM '93. Conference record. 'Communications on the Move'., IEEE , Volume: 3 , 11-14 Oct. 1993
Pages:768 - 773 vol.3

[Abstract] [PDF Full-Text (512 KB)] IEEE CNF

---

42 **IBM Austin Industrial Business Center total productive maintenance - The beginning**

Sanderson, M.; Shelton, M., Jr.; Mulligan, S.;
Electronic Manufacturing Technology Symposium, 1993, Fifteenth IEEE/CHMT International , 4-6 Oct. 1993
Pages:211 - 214

[Abstract] [PDF Full-Text (424 KB)] **IEEE CNF**

---

43 **Competitive manufacturing through total productive maintenance**
Ravishankar, G.; Burczak, C.; De Vore, R.;
Semiconductor Manufacturing Science Symposium, 1992. ISMSS 1992., IEEE/SEMI International , 15-16 June 1992
Pages:85 - 89

[Abstract] [PDF Full-Text (404 KB)] **IEEE CNF**

---

44 **Inert gas wave soldering evaluation**
Altpeter, J.E.; Kneisel, L.L.; Baker, J.D.;
Electronics Manufacturing Technology Symposium, 1991., Eleventh IEEE/CHMT International , 16-18 Sept. 1991
Pages:289 - 293

[Abstract] [PDF Full-Text (304 KB)] **IEEE CNF**

---

45 **LV2Debug: A rule-based tool for the troubleshooting process**
Toms, D.C.; Tenner, D.;
AUTOTESTCON '91. IEEE Systems Readiness Technology Conference. Improving Systems Effectiveness in the Changing Environment of the '90s, Conference Record. , 24-26 Sept. 1991
Pages:249 - 252

[Abstract] [PDF Full-Text (356 KB)] **IEEE CNF**

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---

46 **Analyzing the effect of installing diagnostic equipment in a manufacturing cell**
Lahoti, A.; Kennedy, W.J.;
Reliability and Maintainability Symposium, 1991. Proceedings., Annual , 29-31 Jan. 1991
Pages:10 - 14

[Abstract] [PDF Full-Text (424 KB)] IEEE CNF

---

47 **Application of industry-standard guidelines for the validation of avionics support**
Hayhurst, K.J.; Shagnea, A.M.;
Digital Avionics Systems Conference, 1990. Proceedings., IEEE/AIAA/NASA 9th , 15-18 Oct. 1990
Pages:278 - 282

[Abstract] [PDF Full-Text (444 KB)] IEEE CNF

---

48 **Fault tolerant engineering methodology and the impact on ATE**
Doskocil, D.C.;
AUTOTESTCON '89. IEEE Automatic Testing Conference. The Systems Readiness Technology Conference. Automatic Testing in the Next Decade and the 21st Century. Conference Record. , 25-28 Sept. 1989
Pages:113 - 117

[Abstract] [PDF Full-Text (336 KB)] IEEE CNF

---

49 **A new Coast Guard search technique**
Replogle, F., Jr.;
OCEANS '88. 'A Partnership of Marine Interests'. Proceedings , 31 Oct.-2 Nov. 1988

Pages:1436 - 1438 vol.4

[Abstract] [PDF Full-Text (440 KB)] IEEE CNF

---

50 **Transmission quality of hand-free audio teleconference services**
Kishimoto, N.; Ishimaru, K.; Takahashi, K.;
Communications, 1988. ICC 88. Digital Technology - Spanning the Universe. Conference Record. IEEE International Conference on , 12-15 June 1988
Pages:250 - 254 vol.1

[Abstract] [PDF Full-Text (316 KB)] IEEE CNF

---

51 **Choosing the right tool from the toolbox-some examples of Gemba Kaizen practice**
Burns, A.;
Kaizen: From Understanding to Action (Ref. No. 2000/035), IEE Seminar , 30 March 2000
Pages:6/1 - 6/10

[Abstract] [PDF Full-Text (308 KB)] IEE CNF

---

52 **Electromagnetic screening and crosstalk of ICT access networks**
Halme, L.; Hinoshita, S.; Eriksson, L.; Halmesvaara, M.; Kytonen, R.;
SCreening Effectiveness Measurements (Ref. No. 1998/452), IEE Colloquium on , 6

May 1998
Pages:10/1 - 1020

[Abstract] [PDF Full-Text (840 KB)] IEE CNF

---

53 **Coordination of TCSC and SVC for stability improvement of power systems**
Tso, S.K.; Liang, J.; Zeng, Q.Y.; Lo, K.L.; Zhou, X.X.;
Advances in Power System Control, Operation and Management, 1997. APSCOM-97. Fourth International Conference on (Conf. Publ. No. 450) , Volume: 1 , 11-14 Nov. 1997
Pages:371 - 376 vol.1

[Abstract] [PDF Full-Text (444 KB)] IEE CNF

---

54 **Adaptive countermeasures for high capacity digital radio-relay systems**
Richman, G.D.; Mohamed, S.A.;
Telecommunications, 1989. Second IEE National Conference on , 2-5 Apr 1989
Pages:220 - 225

[Abstract] [PDF Full-Text (440 KB)] IEE CNF

---

55 **Managing, measuring and improving equipment capacity and overall equipment efficiency (OEE) using iPLUS**
Killeen, D.; Gaboury, P.; Paccard, D.;
Semiconductor Manufacturing Symposium, 2001 IEEE International , 8-10 Oct. 2001
Pages:25 - 28

[Abstract] [PDF Full-Text (460 KB)] IEEE CNF

---

56 **Weighted configuration matrix approach to cluster tool metrics**
Dolman, D.; Christian, C.; Qingsu Wang; Crowley, J.;
Semiconductor Manufacturing Conference Proceedings, 1999 IEEE International Symposium on , 11-13 Oct. 1999
Pages:179 - 182

[Abstract] [PDF Full-Text (196 KB)] IEEE CNF

---

57 **Equipment efficiency improvement: the new frontier**
Leachman, R.C.; Busing, D.P.; Ting-Yun Liu; Moore, D.;
Semiconductor Manufacturing Conference Proceedings, 1997 IEEE International Symposium on , 6-8 Oct. 1997
Pages:P39 - P40

[Abstract] [PDF Full-Text (208 KB)] **IEEE CNF**

---

58 **Phase and shape beam evolution in KTP at the exact phase-matched OEE-type cascade process**
Sapojnikov, V.K.; Gorchakov, A.V.; Belostotsky, A.L.; Semenenko, V.V.; Kaplun, A.B.;
Lasers and Electro-Optics, 1997. CLEO '97., Summaries of Papers Presented at the Conference on , Volume: 11 , May 18-23, 1997
Pages:385 - 385

[Abstract] [PDF Full-Text (140 KB)] **IEEE CNF**

---

59 **Overall fab efficiency [semiconductor manufacturing]**
Bonal, J.; Ortega, C.; Rios, L.; Aparicio, S.; Fernandez, M.; Rosendo, M.; Sanchez, A.; Malvar, S.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1996. ASMC 96 Proceedings. IEEE/SEMI 1996 , 12-14 Nov. 1996
Pages:49 - 52

[Abstract] [PDF Full-Text (304 KB)] **IEEE CNF**

---

60 **Policy analysis and decision aids for energy crisis management**
Olson, A.P.; Cha, B.-C.; Laird, W.G.; McColloch, D.L.;
AI Systems in Government Conference, 1989.,Proceedings of the Annual , 27-31 March 1989
Pages:44 - 49

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---

61 **Closed-loop measurement of equipment efficiency and equipment capacity**
Leachman, R.C.;
Semiconductor Manufacturing, IEEE Transactions on , Volume: 10 , Issue: 1 , Feb. 1997
Pages:84 - 97

[Abstract] [PDF Full-Text (240 KB)] IEEE JNL

---

62 **Supplying flexible modular designed assembly equipment to the automotive industry**
Awad, R.;
Electrical Insulation Conference, 1997, and Electrical Manufacturing & Coil Winding Conference. Proceedings , 22-25 Sept. 1997
Pages:121 - 126

[Abstract] [PDF Full-Text (1368 KB)] IEEE CNF

63 **Quantifying operational time variability: the missing parameter for cycle time reduction**
Jacobs, J.H.; Etman, L.F.P.; Rooda, J.E.; Van Campen, E.J.J.;
Advanced Semiconductor Manufacturing Conference, 2001 IEEE/SEMI , 23-24 April 2001
Pages:1 - 10

[Abstract] [PDF Full-Text (764 KB)] IEEE CNF

64 **Remote equipment diagnosis for metal etching process**
Ogata, A.; Iwata, Y.; Yasuharu, I.; Kikuchi, Y.;
Semiconductor Manufacturing Symposium, 2001 IEEE International , 8-10 Oct. 2001
Pages:447 - 450

[Abstract] [PDF Full-Text (565 KB)] IEEE CNF

65 **Closed-loop measurement of equipment efficiency and equipment capacity**
Leachman, R.C.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1995. ASMC 95 Proceedings. IEEE/SEMI 1995 , 13-15 Nov. 1995
Pages:115 - 126

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